

General Description

The HXYG350N10L use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.

This device is specially designed to get better ruggedness.

General Features

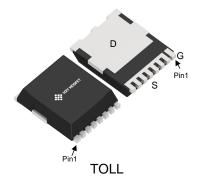
 $V_{DS} = 100V I_{D} = 350A$

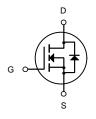
 $R_{DS(ON)} < 2m\Omega$ @ $V_{GS}=10V$

Applications

Battery Protection

Power Distribution





N-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
HXYG350N10L	TOLL	HXY MOSFET	2000

Absolute Maximum Ratings at T_j=25°C unless otherwise noted

Parameter	Symbol	Value	Unit		
Drain-Source Voltage	V _{DS}	100	V		
Gate-Source Voltage		V _{GS}	±20	V	
Continuous Drain Current	T _C =25°C		312		
Continuous Drain Current	T _C =100°C	ID	200	A	
Pulsed Drain Current ¹	I _{DM}	1248	А		
Single Pulse Avalanche Energy ²	EAS	1250	mJ		
Total Power Dissipation T _C =25°C		P _D	390.6	W	
Operating Junction and Storage Temperatu	TJ, Tstg	-55 to 150	°C		
Thermal Resistance from Junction-to-Ambie	R _{0JA}	39	°C/W		
Thermal Resistance from Junction-to-Case	R ₀ JC	0.32	°C/W		



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static Characteristics				- 1	1		
Drain-Source Breakdown Vol	Drain-Source Breakdown Voltage		V _{GS} = 0V, I _D = 250µA	100	-	-	V
Gate-body Leakage current		Igss	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA
Zero Gate Voltage Drain	T _J =25°C	IDSS	V _{DS} = 100V, V _{GS} = 0V	-	-	1	μA
Current	T _J =100°C			-	-	100	
Gate-Threshold Voltage		V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250\mu A$	2	3	4	V
Drain-Source on-Resistance ⁴		R _{DS(on)}	V _{GS} = 10V, I _D = 20A	-	1.4	2.0	mΩ
Forward Transconductance ⁴		g fs	V _{DS} = 10V, I _D =20A	-	84	-	S
Dynamic Characteristics	5						
Input Capacitance		Ciss		-	14300	-	pF
Output Capacitance		Coss	V _{DS} = 50V, V _{GS} =0V, f =1MHz	-	2120	-	
Reverse Transfer Capacitance		Crss	· ····· -	-	50	-	
Gate Resistance		Rg	f=1MHz	-	2.8	-	Ω
Switching Characteristic	: s ⁵			•			
Total Gate Charge		Qg	V _{GS} = 10V, V _{DS} = 50V, I _D = 20A	-	250	-	nC
Gate-Source Charge		Q _{gs}		-	53	-	
Gate-Drain Charge		Q _{gd}		-	77	-	
Turn-on Delay Time		t _{d(on)}		-	41	-	
Rise Time		t r	$V_{GS} = 10V, V_{DD} = 50V,$ $R_{G} = 3\Omega, I_{D} = 20A$	-	88	-	ns
Turn-off Delay Time		t _{d(off)}		-	163	-	
Fall Time		t f		-	98	-	
Body Diode Reverse Recovery Time		t _{rr}		-	106	-	ns
Body Diode Reverse Recovery Charge		Qrr	- I _F =20A, di/dt = 100A/μs	-	245	-	nC
Drain-Source Body Diode Characteristics							
Diode Forward Voltage ⁴		V _{SD}	I _S = 20A, V _{GS} = 0V	-	-	1.2	V
Continuous Source Current T _C =25°C		Is	-	-	-	312	Α

Note:

- 1. The maximum current rating is package limited.
- Repetitive rating; pulse width limited by max. junction temperature.
- V_{DD} =32 V, R_G =25 Ω , L=0.5mH, starting T_j =25°C.
- P_D is based on max. junction temperature, using junction-case thermal resistance. The value of R_{BJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with Ta=25°C.



Typical Characteristics

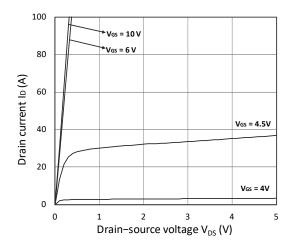


Figure 1. Output Characteristics

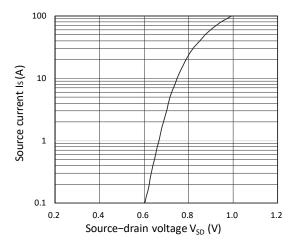


Figure 3. Forward Characteristics of Reverse

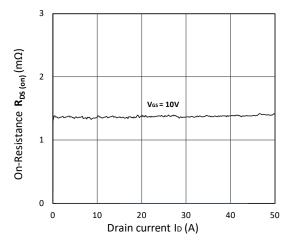


Figure 5. $R_{DS(ON)}$ vs. I_D

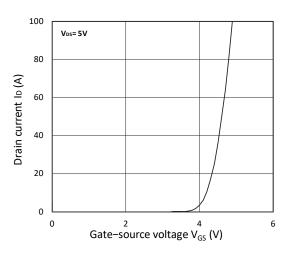


Figure 2. Transfer Characteristics

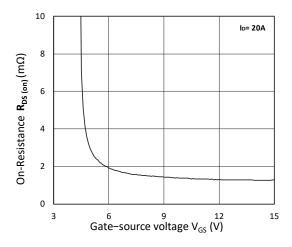


Figure 4. $R_{\text{DS}(\text{ON})}\,$ vs. V_{GS}

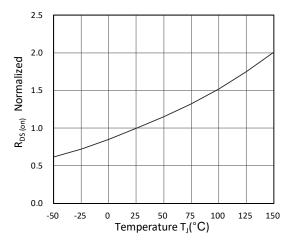


Figure 6. Normalized $R_{\text{DS(on)}}$ vs. Temperature

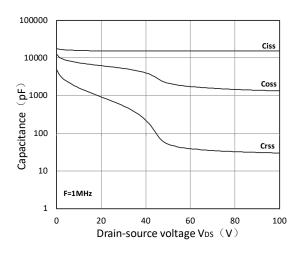


Figure 7. Capacitance Characteristics

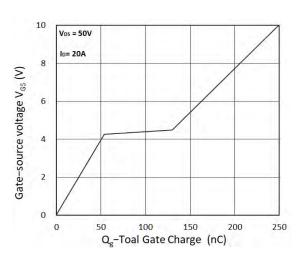


Figure 8. Gate Charge Characteristics

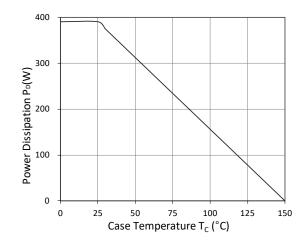


Figure 9. Power Dissipation

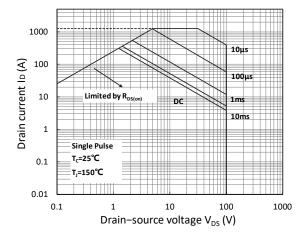


Figure 10. Safe Operating Area

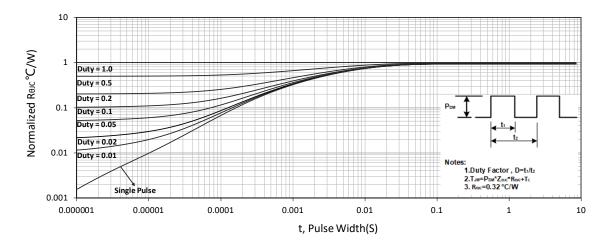


Figure 11. Normalized Maximum Transient Thermal Impedance

Test Circuit

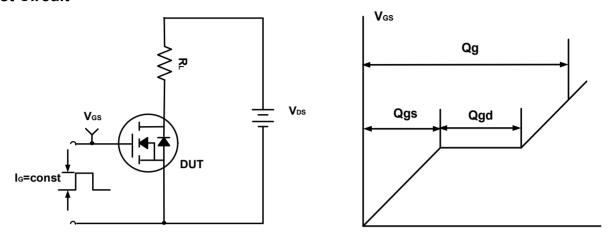


Figure A. Gate Charge Test Circuit & Waveforms

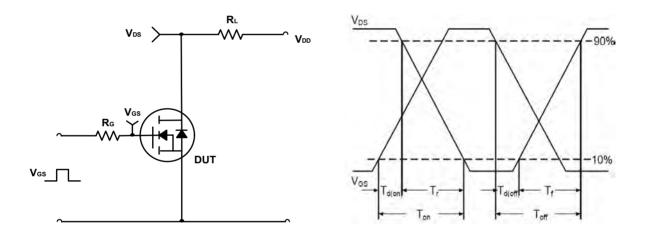


Figure B. Switching Test Circuit & Waveforms

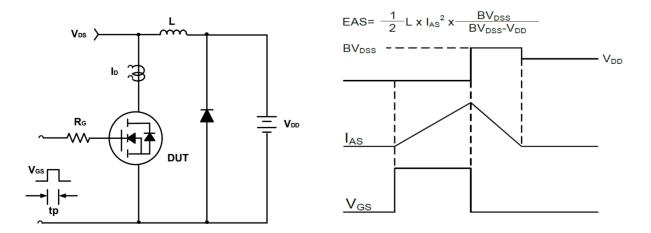
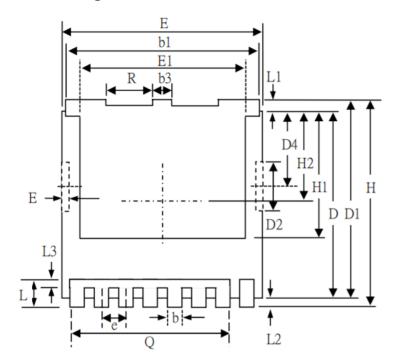


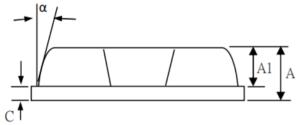
Figure C. Unclamped Inductive Switching Circuit & Waveforms



TOLL Package Information



RL	Γ	KSI	DE '	VIE	αM
$\mathbf{D}_{\mathcal{L}}$	\sim	$\Gamma Z \cap \Gamma$	בעב	V 11	2 Y Y



C T			

- 1.All Dimension Are In Millimeters.
- 2. Dimension Does Not Include Mold Protrusions.

Cumbal	mm				
Symbol	Min	Max			
А	2.20	2.40			
b	0.60	0.90			
b1	9.70	9.90			
С	0.40	0.60			
D	10.20	10.60			
D1	3.10	3.50			
D2	4.45	4.75			
Е	9.70	10.10			
E1	7.80BSC				
E2	0.50	0.70			
е	1.200	BSC			
Н	11.45	11.90			
H1	6.75	BSC			
K	3.10 REF				
L	1.70	2.10			
L1	0.60	0.80			
L2	0.50	0.70			
θ	10° REF				



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